PCN Number: 201		70203000			PCN Date:		: Feb 6, 2017		
Title: UCD3138128PFC/U			UCD3138A64PFC Product Family Die Revision Change						
Customer Contact:			PCN Manager			Dep	Dept:		Quality Services
Proposed 1 st Ship Date:			May 6, 2017 Estimated Sample			ple			Date provided at
Proposed 1 Ship Date.		Availability:			sample request.				
Change Type:									
Assembly Site			Assembly Process				Assembly Materials		
Design			Electrical Specification				Mechanical Specification		
Test Site		Packing/Shipping/Labeling				Test Process			
Wafer Bump Site		☐ Wafer Bump Material					Wafer Bump Process		
Wafer Fab Site			Wafer Fab Materials				Wafer Fab Process		
			Part number change						
PCN Details									

Description of Change:

This potification is to info

This notification is to inform of a die revision change to the UCD3138128PFC/UCD3138A64PFC family of devices. A design change was performed to tighten program current distribution by 20% for better yield control. There will be no accompanying changes to the device specifications. The design changes do not affect the device's guaranteed datasheet specifications or electrical performance.

Affected devices are listed in the product affected section of this document.

Reason for Change:

Improved yield control

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Die Rev designator will change as shown in the table and sample label below:

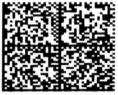
 Current
 New

 Die Rev [2P]
 Die Rev [2P]

 A
 C

Sample product shipping label (not actual product label)







Product Affected:

UCD3138128PFC UCD3138128PFCR UCD3138A64PFC UCD3138A64PFCR	
---	--

Qualification Report UCD3138128PFC /UCD3138A64PFC Design Change Approve Date 10-Oct-2016

Product Attributes

Attributes	Qual Device: UCD3138128PFC	Qual Device: UCD3138A64PFC	QBS Product Reference: UCD3138A64QPFCRQ1
Assembly Site	TITL (TAI)	TITL (TAI)	TITL (TAI)
Package Family	QFP	QFP	QFP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	TSMC 11	TSMC 11	TSMC 11
Wafer Process	TSMC 0.18	TSMC 0.18	TSMC 0.18

- QBS: Qual By Similarity Qual Device UCD3138A64PFC is qualified at LEVEL3-260C
- Qual Device UCD3138128PFC is qualified at LEVEL3-260CG

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: UCD3138128PFC	Qual Device: UCD3138A64PFC	QBS Product Reference: UCD3138A64QPFCRQ1
AC	Autoclave 121C	96 Hours	-	-	3/231/0
ED	Auto Electrical Distributions	Cpk>1.67 Room, hot, and cold test	-	-	Pass
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	3/2400/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0
HBM	ESD - HBM	4000 V	1/3/0	-	1/3/0
CDM	ESD - CDM	1500 V	1/3/0	-	-
HTOL	Life Test, 140C	480 Hours	-	-	1/77/0
LU	Latch-up	(per JESD78)	1/6/0	-	1/6/0
PD	Physical Dimensions		-	-	Pass
SD	Solderability	Pb Free	-	-	3/45/0
SD	Solderability	Pb	-	-	3/45/0
TC	Temperature Cycle, - 65/150C	500 Cycles	-	-	3/231/0
WBP	Bond Pull	Wires	-	-	Pass
WBS	Bond Shear	Wires	-	-	Pass

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

 The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

 The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

 The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

 Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com